

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC4093BP, TC4093BF, TC4093BFN

## TC4093B Quad 2-Input NAND Schmitt Triggers

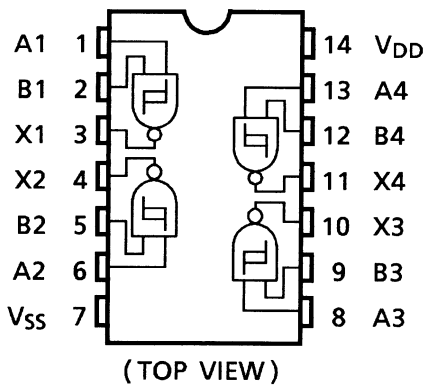
The TC4093B is a quad 2-input NAND gate having Schmitt trigger function for all the input terminals.

Since the circuit threshold voltage varies with rising time and falling time of the input waveform ( $V_P$  and  $V_N$ ), this gate can be used for a wide variety of applications to line receivers, waveform shaping, astable multivibrators, monostable multivibrators, etc.

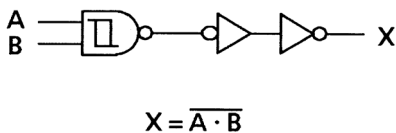
In addition to regular NAND gates.

As the TC4093B and the TC4011B are identical in pin assignment, they are compatible each other.

### Pin Assignment

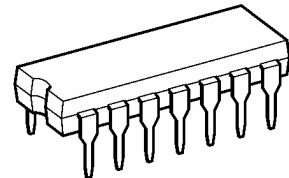


### Logic Diagram



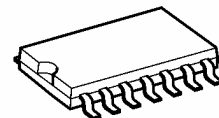
Note: xxxFN (JEDEC SOP) is not available in Japan.

TC4093BP

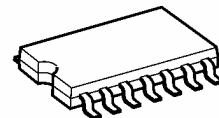


DIP14-P-300-2.54

TC4093BF

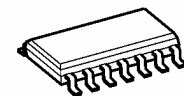


SOP14-P-300-1.27A



SOP14-P-300-1.27

TC4093BFN

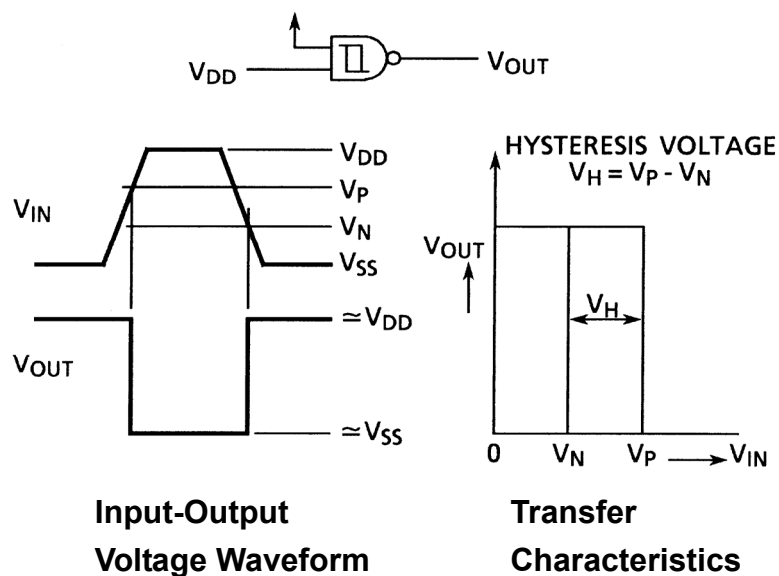


SOL14-P-150-1.27

### Weight

DIP14-P-300-2.54	: 0.96 g (typ.)
SOP14-P-300-1.27A	: 0.18 g (typ.)
SOP14-P-300-1.27	: 0.18 g (typ.)
SOL14-P-150-1.27	: 0.12 g (typ.)

## Input-Output Characteristic



## Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	$V_{SS} - 0.5 \sim V_{SS} + 20$	V
Input voltage	$V_{IN}$	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
Output voltage	$V_{OUT}$	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
DC input current	$I_{IN}$	$\pm 10$	mA
Power dissipation	$P_D$	300 (DIP)/180 (SOIC)	mW
Operating temperature range	$T_{opr}$	$-40 \sim 85$	$^{\circ}\text{C}$
Storage temperature range	$T_{stg}$	$-65 \sim 150$	$^{\circ}\text{C}$

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

## Recommended Operating Conditions ( $V_{SS} = 0 \text{ V}$ ) (Note)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
DC supply voltage	$V_{DD}$	—	3	—	18	V
Input voltage	$V_{IN}$	—	0	—	$V_{DD}$	V

Note: The recommended operating conditions are required to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Static Electrical Characteristics ( $V_{SS} = 0\text{ V}$ )

Characteristics		Sym- bol	Test Condition	-40°C			25°C			85°C		Unit
				$V_{DD}$ (V)	Min	Max	Min	Typ.	Max	Min	Max	
High-level output voltage		$V_{OH}$	$ I_{OUT}  < 1\text{ }\mu\text{A}$ $V_{IN} = V_{SS}, V_{DD}$	5	4.95	—	4.95	5.00	—	4.95	—	V
				10	9.95	—	9.95	10.00	—	9.95	—	
				15	14.95	—	14.95	15.00	—	14.95	—	
Low-level output voltage		$V_{OL}$	$ I_{OUT}  < 1\text{ }\mu\text{A}$ $V_{IN} = V_{DD}$	5	—	0.05	—	0.00	0.05	—	0.05	V
				10	—	0.05	—	0.00	0.05	—	0.05	
				15	—	0.05	—	0.00	0.05	—	0.05	
Output high current		$I_{OH}$	$V_{OH} = 4.6\text{ V}$	5	-0.61	—	-0.51	-1.0	—	-0.42	—	mA
			$V_{OH} = 2.5\text{ V}$	5	-2.50	—	-2.10	-4.0	—	-1.70	—	
			$V_{OH} = 9.5\text{ V}$	10	-1.50	—	-1.30	-2.2	—	-1.10	—	
			$V_{OH} = 13.5\text{ V}$	15	-4.00	—	-3.40	-9.0	—	-2.80	—	
			$V_{IN} = V_{SS}, V_{DD}$									
Output low current		$I_{OL}$	$V_{OL} = 0.4\text{ V}$	5	0.61	—	0.51	1.5	—	0.42	—	mA
			$V_{OL} = 0.5\text{ V}$	10	1.5	—	1.30	3.8	—	1.10	—	
			$V_{OL} = 1.5\text{ V}$	15	4.0	—	3.40	15.0	—	2.80	—	
			$V_{IN} = V_{DD}$									
High threshold voltage		$V_P$	$V_{OUT} = 0.5\text{ V}, 4.5\text{ V}$	5	—	—	2.05	2.8	3.55	—	—	V
			$V_{OUT} = 1.0\text{ V}, 9.0\text{ V}$	10	—	—	4.10	5.3	7.00	—	—	
			$V_{OUT} = 1.5\text{ V}, 13.5\text{ V}$	15	—	—	6.20	7.8	10.40	—	—	
Low threshold voltage		$V_N$	$V_{OUT} = 0.5\text{ V}, 4.5\text{ V}$	5	—	—	1.5	2.3	3.15	—	—	V
			$V_{OUT} = 1.0\text{ V}, 9.0\text{ V}$	10	—	—	3.2	4.5	6.30	—	—	
			$V_{OUT} = 1.5\text{ V}, 13.5\text{ V}$	15	—	—	4.8	6.6	9.30	—	—	
Hysteresis voltage		$V_H$	—	5	—	—	0.20	0.5	0.85	—	—	V
				10	—	—	0.30	0.8	1.40	—	—	
				15	—	—	0.45	1.2	1.90	—	—	
Input current	"H" level	$I_{IH}$	$V_{IH} = 18\text{ V}$	18	—	0.1	—	$10^{-5}$	0.1	—	1.0	$\mu\text{A}$
	"L" level	$I_{IL}$	$V_{IL} = 0\text{ V}$	18	—	-0.1	—	$-10^{-5}$	-0.1	—	-1.0	
Quiescent supply current		$I_{DD}$	$V_{IN} = V_{SS}, V_{DD}$ (Note)	5	—	1	—	0.001	1	—	7.5	$\mu\text{A}$
				10	—	2	—	0.002	2	—	15.0	
				15	—	4	—	0.004	4	—	30.0	

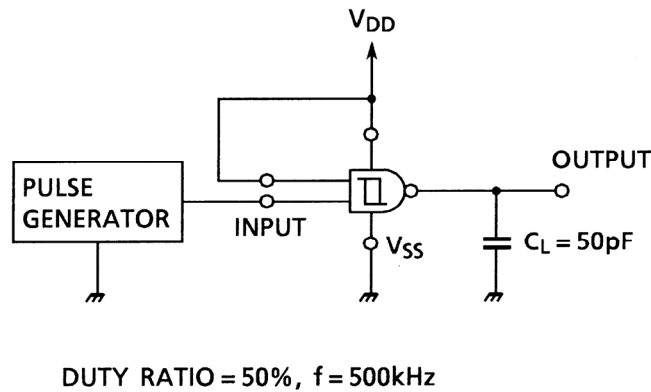
Note: All valid input combinations.

Dynamic Electrical Characteristics (Ta = 25°C, VSS = 0 V, CL = 50 pF)

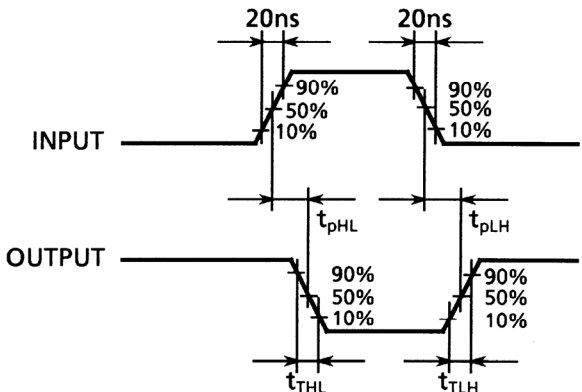
Characteristics	Symbol	Test Condition	VDD (V)	Min	Typ.	Max	Unit
Output transition time (low to high)	tTLH	—	5	—	80	200	ns
			10	—	50	100	
			15	—	40	80	
Output transition time (high to low)	tTHL	—	5	—	80	200	ns
			10	—	50	100	
			15	—	40	80	
Propagation delay time	tPLH tPHL	—	5	—	130	260	ns
			10	—	60	120	
			15	—	40	80	
Input capacitance	CIN	—		—	5	7.5	pF

Circuit and Waveform for Measurement of Dynamic Characteristics

Circuit



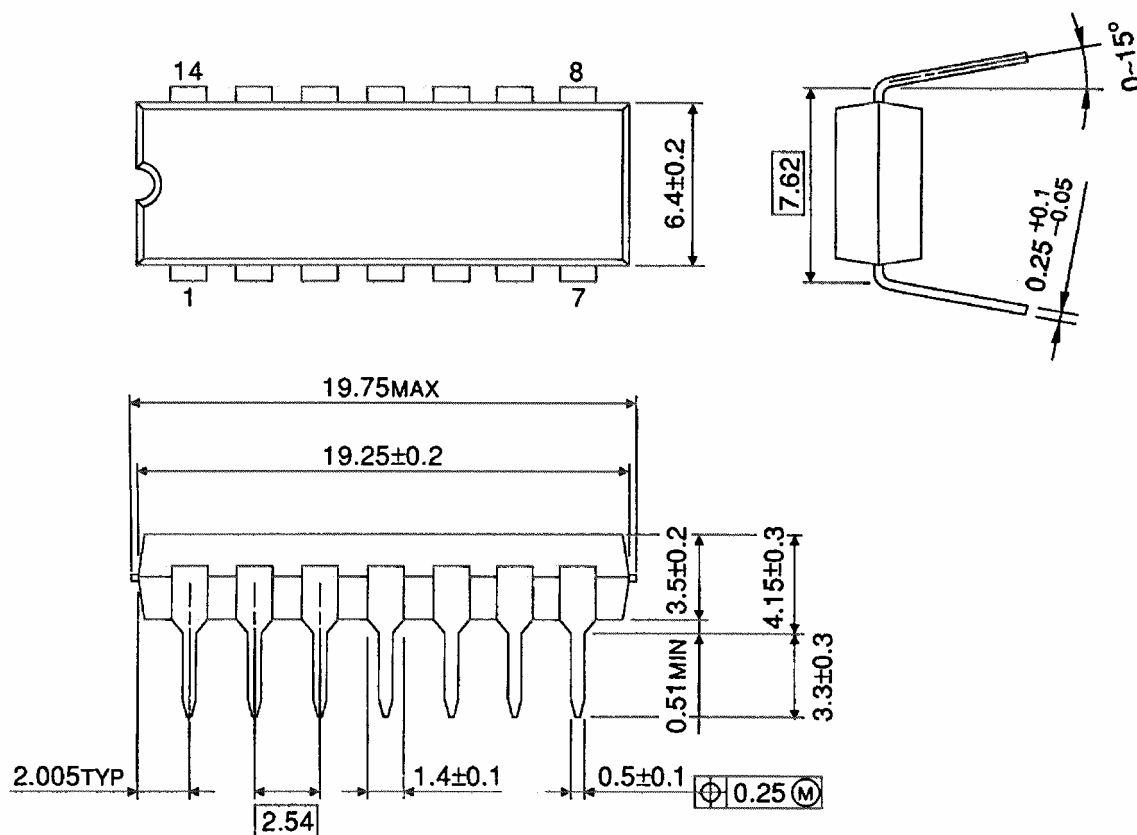
Waveform



## Package Dimensions

DIP14-P-300-2.54

Unit : mm

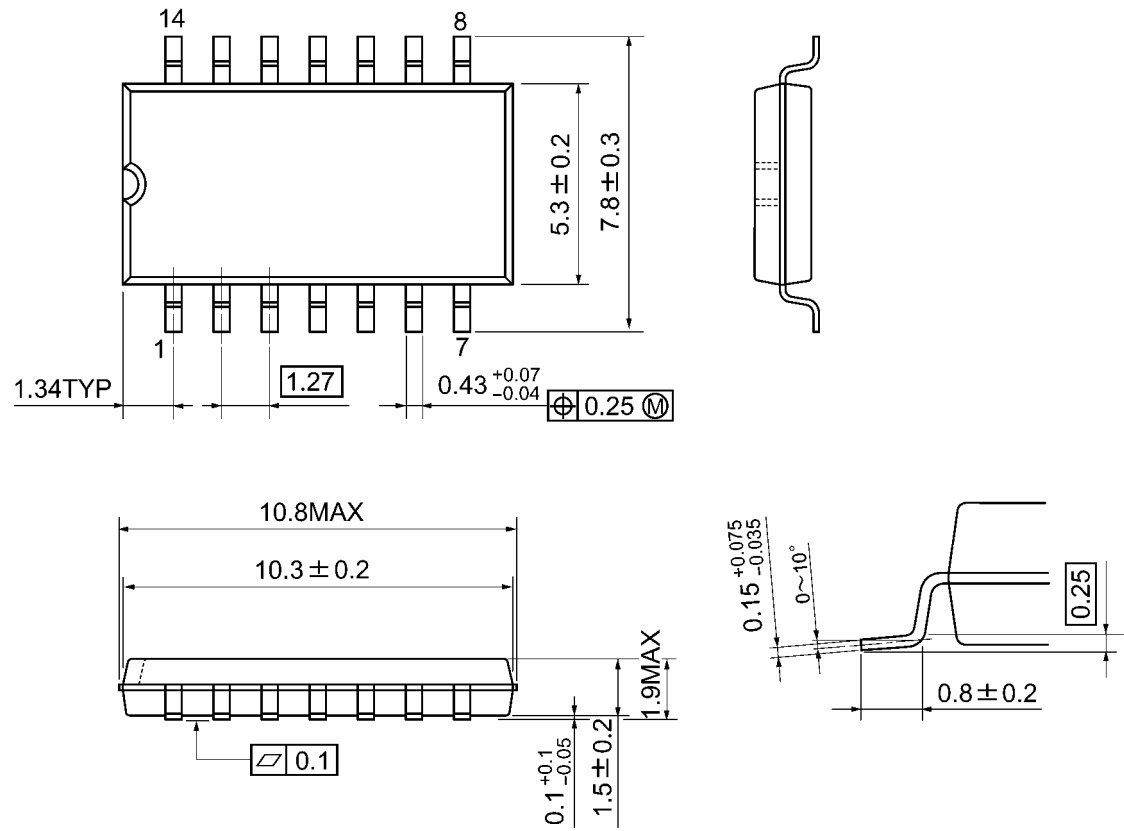


Weight: 0.96 g (typ.)

Package Dimensions

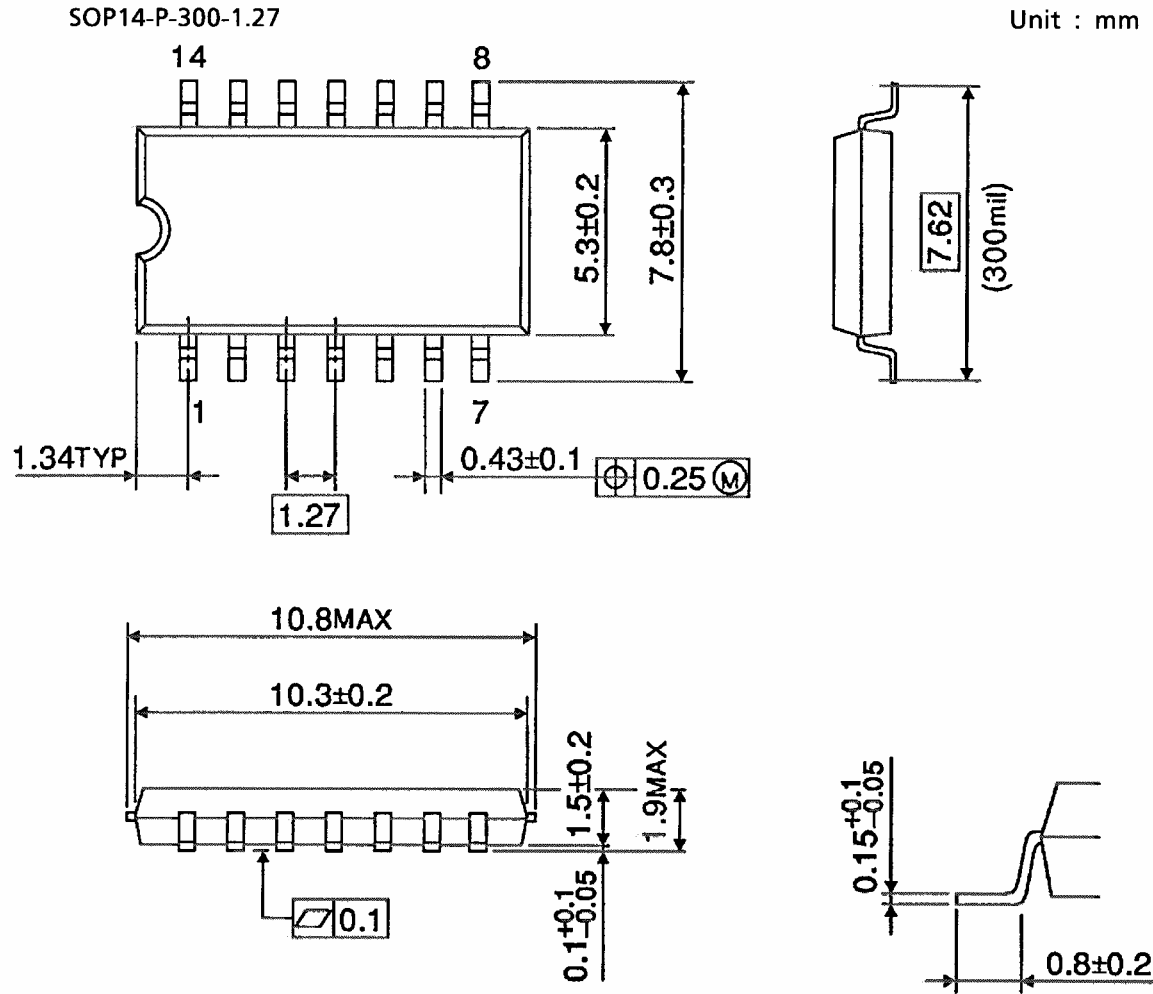
SOP14-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)

Package Dimensions

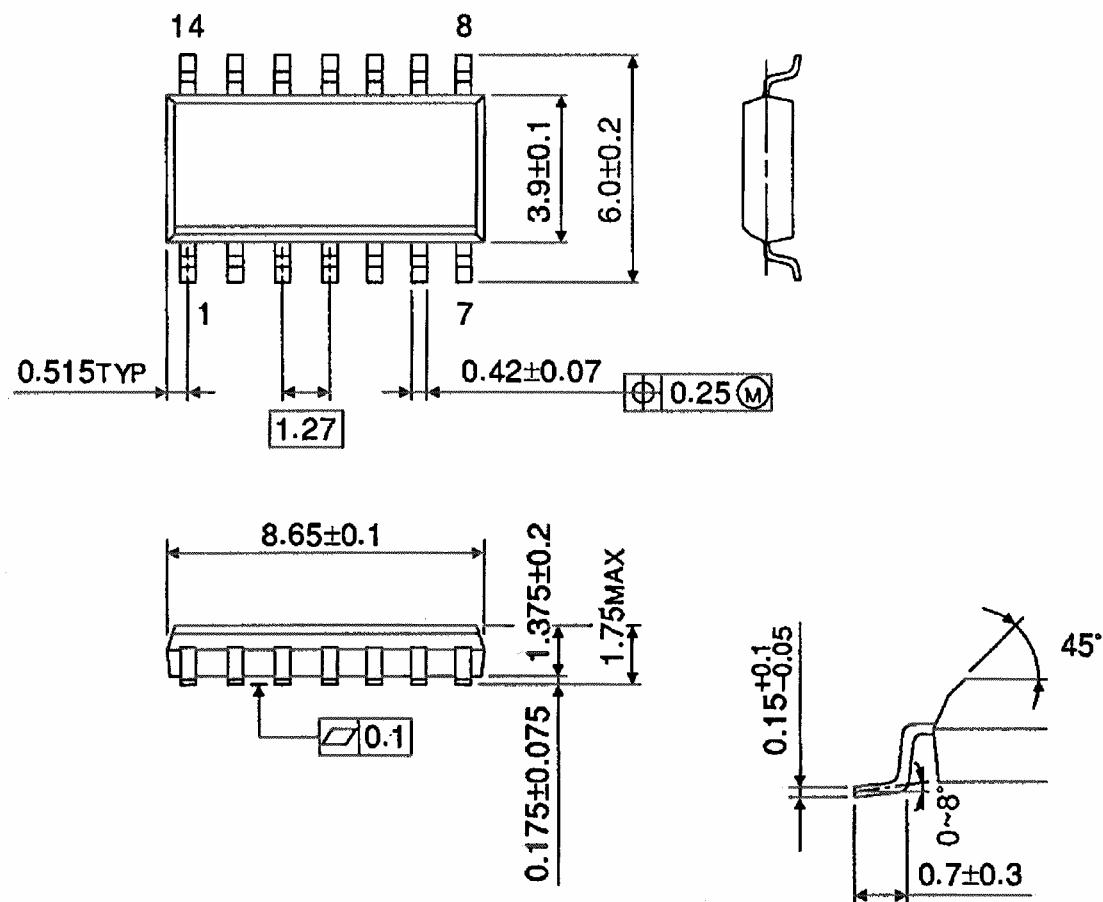


Weight: 0.18 g (typ.)

## Package Dimensions (Note)

SOL14-P-150-1.27

Unit : mm



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)



**Note: Lead (Pb)-Free Packages****DIP14-P-300-2.54   SOP14-P-300-1.27A   SOL14-P-150-1.27****RESTRICTIONS ON PRODUCT USE**

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